


<b>Search Notes</b> 	<b>Application/Control No.</b> 10604567	<b>Applicant(s)/Patent Under Reexamination</b> LIN ET AL.
	<b>Examiner</b> Hung, Yubin	<b>Art Unit</b> 2624

SEARCHED			
Class	Subclass	Date	Examiner
375	240.13, 240.24	06/04/07	YH
382	166, 234, 238, 250	06/04/07	YH
348	394.1	06/04/07	YH

SEARCH NOTES		
Search Notes	Date	Examiner
EAST Text search (USPGPUB, USPAT, EPO, JPO, DERWENT, IBM-TDB)	06/04/07	YH
ACM	12/13/06	YH
IEEE Xplore	12/13/06	YH
SPIE	12/13/06	YH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
382	234, 238	6/4/07	YH
348	394.1	6/4/07	YH
375	240.24	6/4/07	YH